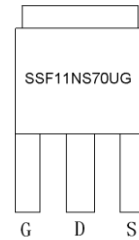


## Main Product Characteristics

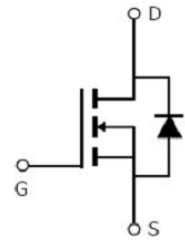
|              |                      |
|--------------|----------------------|
| $V_{DS}$     | 700V                 |
| $R_{DS(on)}$ | 0.39 $\Omega$ (typ.) |
| $I_D$        | 11A                  |



TO-251 (IPAK)



Marking and Pin  
Assignment



Schematic Diagram

## Features and Benefits

- High dv/dt and avalanche capabilities
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance



## Description

The SSF11NS70UG series MOSFETs is a new technology, which combines an innovative technology and advance process. This new technology achieves low Rdson, energy saving, high reliability and uniformity, superior power density and space saving.

## Absolute Max Rating

| Symbol             | Parameter                                             | Max.        | Units |
|--------------------|-------------------------------------------------------|-------------|-------|
| $I_D$ @ TC = 25°C  | Continuous Drain Current, $V_{GS}$ @ 10V <sup>①</sup> | 11          | A     |
| $I_D$ @ TC = 100°C | Continuous Drain Current, $V_{GS}$ @ 10V <sup>①</sup> | 7           |       |
| $I_{DM}$           | Pulsed Drain Current <sup>②</sup>                     | 44          |       |
| $P_D$ @TC = 25°C   | Power Dissipation <sup>③</sup>                        | 40          | W     |
|                    | Linear Derating Factor                                | 0.32        | W/°C  |
| $V_{DS}$           | Drain-Source Voltage                                  | 700         | V     |
| $V_{GS}$           | Gate-to-Source Voltage                                | ± 30        | V     |
| $E_{AS}$           | Single Pulse Avalanche Energy @ L=133mH               | 160         | mJ    |
| $I_{AS}$           | Avalanche Current @ L=133mH                           | 1.55        | A     |
| $T_J$ $T_{STG}$    | Operating Junction and Storage Temperature Range      | -55 to +150 | °C    |

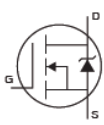
## Thermal Resistance

| Symbol          | Characteristics                                   | Typ. | Max. | Units |
|-----------------|---------------------------------------------------|------|------|-------|
| $R_{\theta JC}$ | Junction-to-case <sup>③</sup>                     | —    | 3.1  | °C/W  |
| $R_{\theta JA}$ | Junction-to-ambient ( $t \leq 10s$ ) <sup>④</sup> | —    | 62   | °C/W  |

## Electrical Characteristics @ $T_A=25^\circ\text{C}$ unless otherwise specified

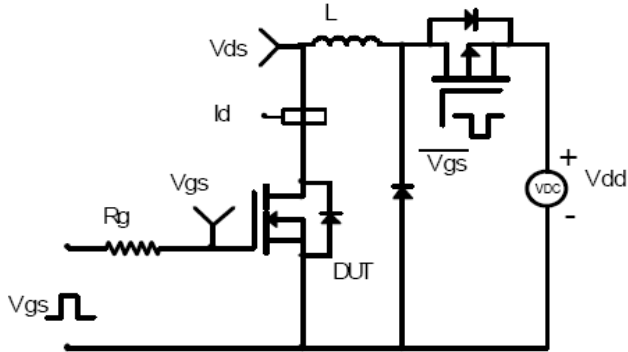
| Symbol        | Parameter                            | Min. | Typ. | Max. | Units    | Conditions                                                                      |
|---------------|--------------------------------------|------|------|------|----------|---------------------------------------------------------------------------------|
| $V_{(BR)DSS}$ | Drain-to-Source breakdown voltage    | 700  | —    | —    | V        | $V_{GS} = 0V, I_D = 250\mu A$                                                   |
| $R_{DS(on)}$  | Static Drain-to-Source on-resistance | —    | 0.39 | 0.45 | $\Omega$ | $V_{GS}=10V, I_D = 3.2A$                                                        |
|               |                                      | —    | 0.85 | —    |          | $T_J = 125^\circ\text{C}$                                                       |
| $V_{GS(th)}$  | Gate threshold voltage               | 2    | —    | 4    | V        | $V_{DS} = V_{GS}, I_D = 250\mu A$                                               |
|               |                                      | —    | 2.28 | —    |          | $T_J = 125^\circ\text{C}$                                                       |
| $I_{DSS}$     | Drain-to-Source leakage current      | —    | —    | 1    | $\mu A$  | $V_{DS} = 700V, V_{GS} = 0V$                                                    |
|               |                                      | —    | —    | 50   |          | $T_J = 125^\circ\text{C}$                                                       |
| $I_{GSS}$     | Gate-to-Source forward leakage       | —    | —    | 100  | nA       | $V_{GS} = 30V$                                                                  |
|               |                                      | —    | —    | -100 |          | $V_{GS} = -30V$                                                                 |
| $Q_g$         | Total gate charge                    | —    | 21   | —    | nC       | $I_D = 6A,$                                                                     |
| $Q_{gs}$      | Gate-to-Source charge                | —    | 5.1  | —    |          | $V_{DS} = 200V,$                                                                |
| $Q_{gd}$      | Gate-to-Drain("Miller") charge       | —    | 7.3  | —    |          | $V_{GS} = 10V$                                                                  |
| $t_{d(on)}$   | Turn-on delay time                   | —    | 11   | —    | ns       | $V_{GS}=10V, V_{DS}=400V,$<br>$R_L=81.6\Omega, R_{GEN}=3.4\Omega$<br>$I_D=4.9A$ |
| $t_r$         | Rise time                            | —    | 6.9  | —    |          |                                                                                 |
| $t_{d(off)}$  | Turn-Off delay time                  | —    | 26   | —    |          |                                                                                 |
| $t_f$         | Fall time                            | —    | 6.7  | —    |          |                                                                                 |
| $C_{iss}$     | Input capacitance                    | —    | 825  | —    | pF       | $V_{GS} = 0V$                                                                   |
| $C_{oss}$     | Output capacitance                   | —    | 31   | —    |          | $V_{DS} = 100V$                                                                 |
| $C_{rss}$     | Reverse transfer capacitance         | —    | 3.0  | —    |          | $f = 600KHz$                                                                    |

## Source-Drain Ratings and Characteristics

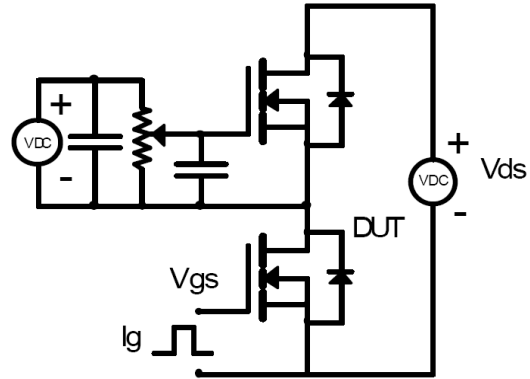
| Symbol   | Parameter                                 | Min. | Typ. | Max. | Units   | Conditions                                                                                                                                                       |
|----------|-------------------------------------------|------|------|------|---------|------------------------------------------------------------------------------------------------------------------------------------------------------------------|
| $I_S$    | Continuous Source Current<br>(Body Diode) | —    | —    | 11   | A       | MOSFET symbol<br>showing the<br>integral reverse<br>p-n junction diode.<br> |
| $I_{SM}$ | Pulsed Source Current<br>(Body Diode)     | —    | —    | 44   | A       |                                                                                                                                                                  |
| $V_{SD}$ | Diode Forward Voltage                     | —    | 0.81 | 1.2  | V       | $I_S=4.9A, V_{GS}=0V$                                                                                                                                            |
| $t_{rr}$ | Reverse Recovery Time                     | —    | 237  | —    | ns      | $T_J = 25^\circ\text{C}, I_F = 11A,$<br>$di/dt = 100A/\mu s$                                                                                                     |
| $Q_{rr}$ | Reverse Recovery Charge                   | —    | 2.4  | —    | $\mu C$ |                                                                                                                                                                  |

## Test circuits and Waveforms

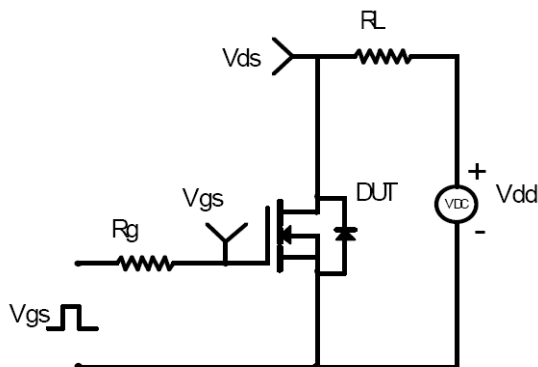
EAS Test Circuit:



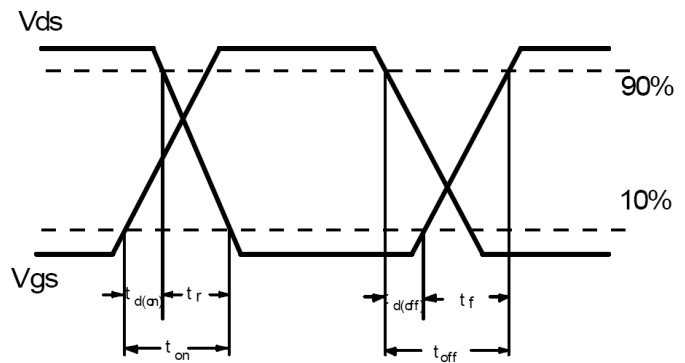
Gate charge test circuit:



Switching Time Test Circuit:



Switching Waveforms:



## Notes:

- ① Calculated continuous current based on maximum allowable junction temperature.
- ② Repetitive rating; pulse width limited by max. junction temperature.
- ③ The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- ④ The value of  $R_{\theta JA}$  is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A = 25^\circ\text{C}$

## Typical electrical and thermal characteristics

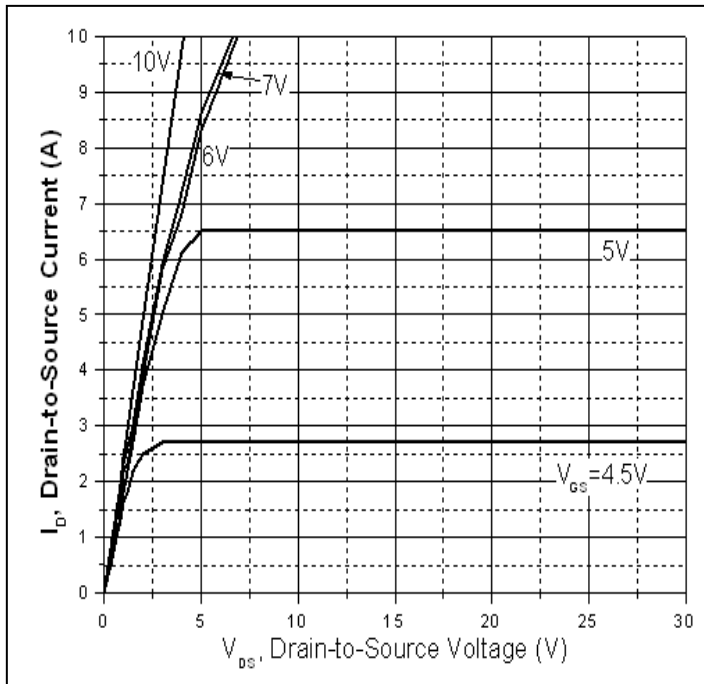


Figure 1: Typical Output Characteristics

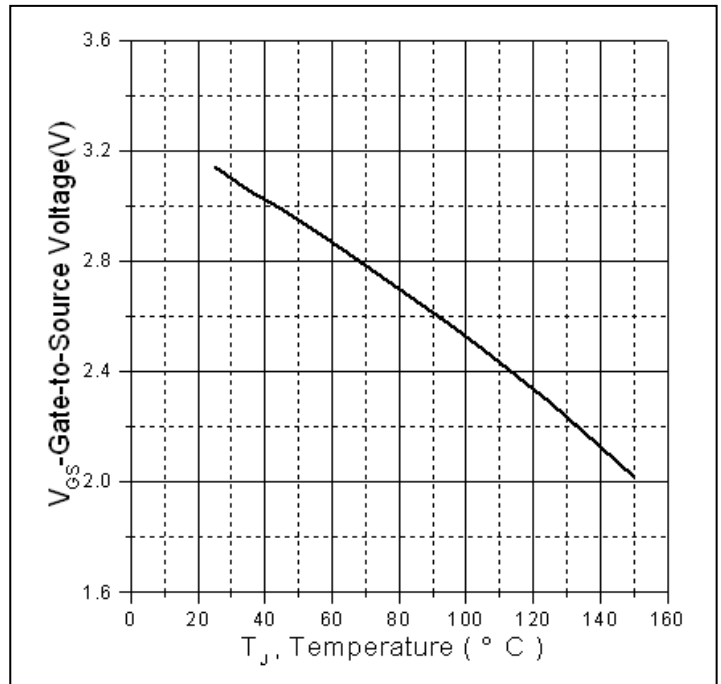


Figure 2. Gate to source cut-off voltage

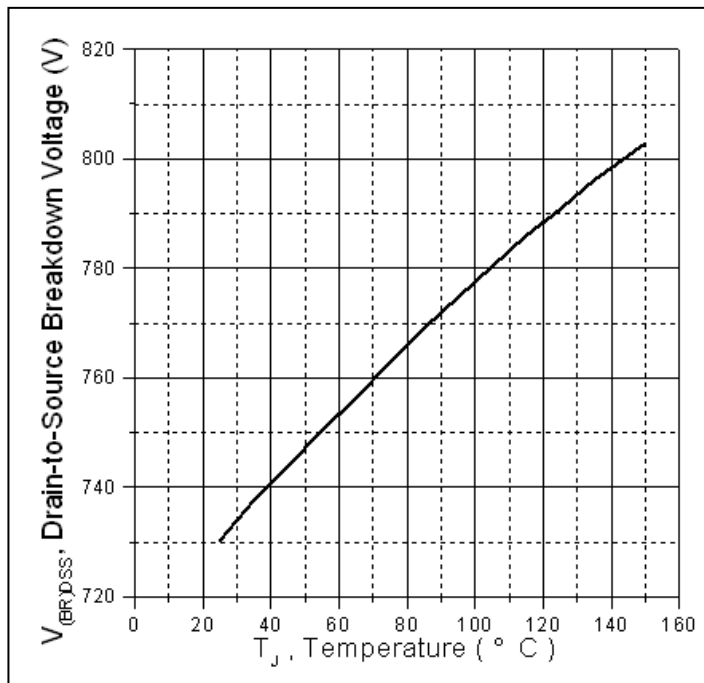


Figure 3. Drain-to-Source Breakdown Voltage Vs. Case Temperature

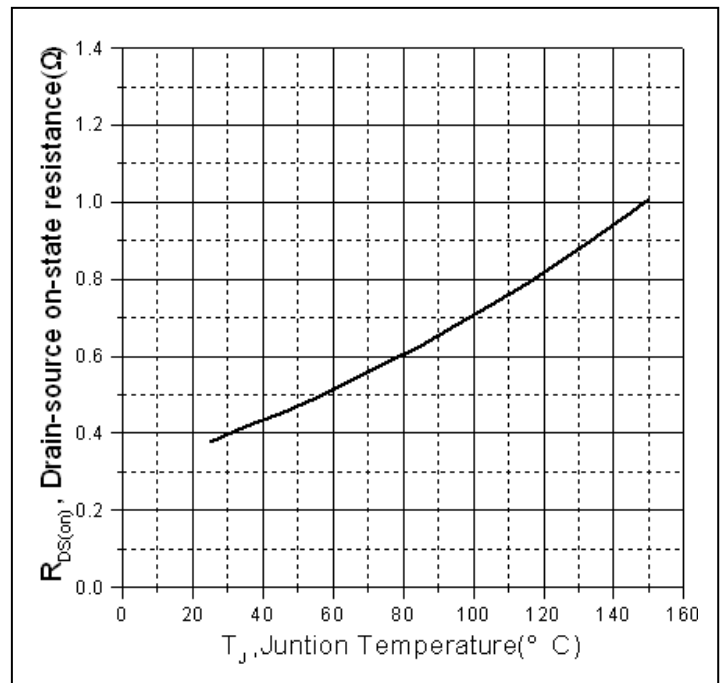
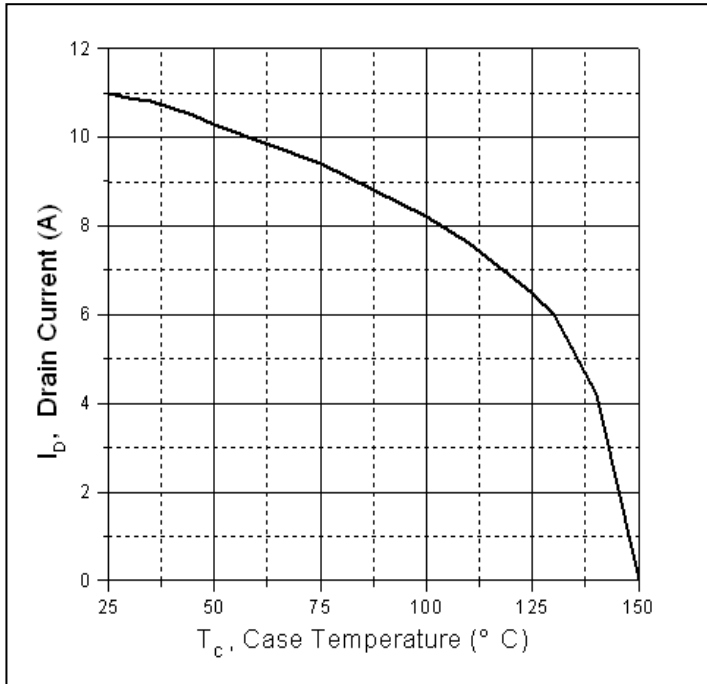
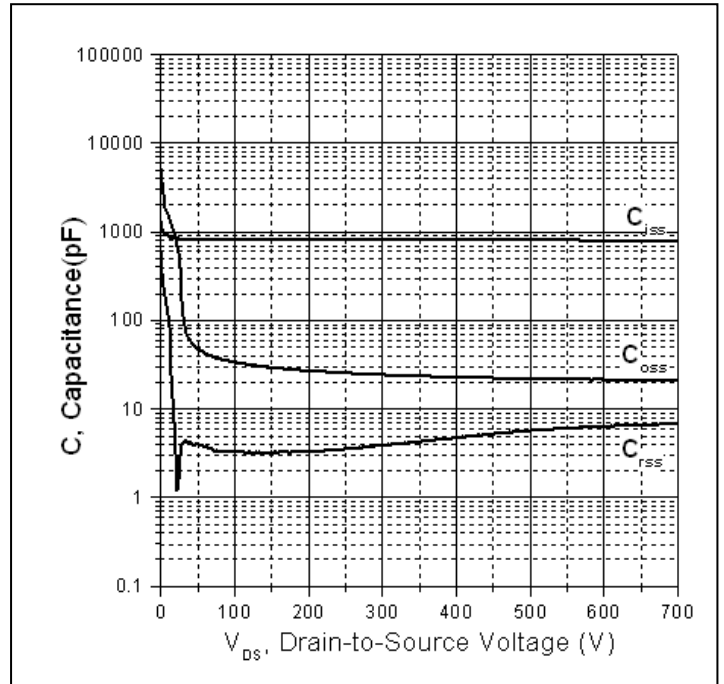


Figure 4: Normalized On-Resistance Vs. Case Temperature

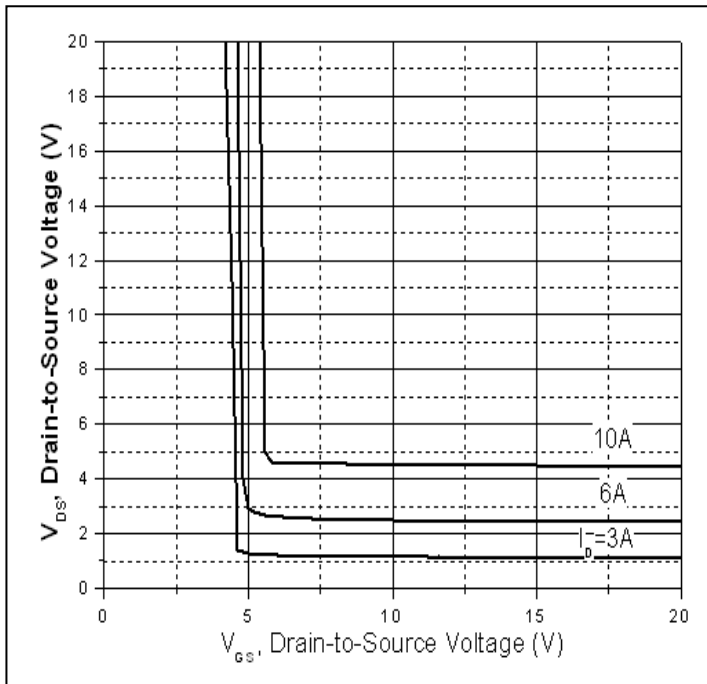
## Typical electrical and thermal characteristics



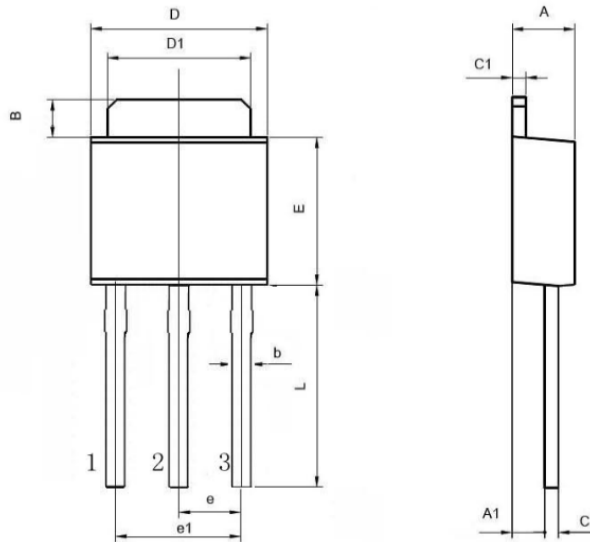
**Figure 5. Maximum Drain Current Vs. Case Temperature**



**Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage**



**Figure7. Drain-to-Source Voltage Vs. Gate-to-Source Voltage**

**Mechanical Data:**
**TO-251 PACKAGE OUTLINE DIMENSION**


| Symbol | Dimension In Millimeters |     |       | Dimension In Inches |     |       |
|--------|--------------------------|-----|-------|---------------------|-----|-------|
|        | Min                      | Nom | Max   | Min                 | Nom | Max   |
| A      | 2.200                    | -   | 2.400 | 0.087               | -   | 0.094 |
| A1     | 0.950                    | -   | 1.150 | 0.037               | -   | 0.045 |
| B      | 0.950                    | -   | 1.250 | 0.037               | -   | 0.049 |
| b      | 0.500                    | -   | 0.700 | 0.020               | -   | 0.028 |
| c      | 0.450                    | -   | 0.550 | 0.018               | -   | 0.022 |
| c1     | 0.450                    | -   | 0.550 | 0.018               | -   | 0.022 |
| D      | 6.450                    | -   | 6.750 | 0.254               | -   | 0.266 |
| D1     | 5.200                    | -   | 5.400 | 0.205               | -   | 0.213 |
| E      | 5.950                    | -   | 6.250 | 0.234               | -   | 0.246 |
| e      | 2.240                    | -   | 2.340 | 0.088               | -   | 0.092 |
| e1     | 4.430                    | -   | 4.730 | 0.174               | -   | 0.186 |
| L      | 9.000                    | -   | 9.400 | 0.354               | -   | 0.370 |

**Ordering and Marking Information****Device Marking: SSF11NS70UG****Package (Available)****TO-251(IPAK)****Operating Temperature Range****C : -55 to 150 °C****Devices per Unit**

| <b>Package Type</b> | <b>Units/ Tube</b> | <b>Tubes/Inner Box</b> | <b>Units/Inner Box</b> | <b>Inner Boxes/Carton Box</b> | <b>Units/Carton Box</b> |
|---------------------|--------------------|------------------------|------------------------|-------------------------------|-------------------------|
| TO-251              | 75                 | 60                     | 4500                   | 5                             | 225000                  |

**Reliability Test Program**

| <b>Test Item</b>                    | <b>Conditions</b>                                            | <b>Duration</b>                      | <b>Sample Size</b>  |
|-------------------------------------|--------------------------------------------------------------|--------------------------------------|---------------------|
| High Temperature Reverse Bias(HTRB) | $T_j=150^{\circ}\text{C}$ @ 80% of Max $V_{DSS}/V_{CES}/V_R$ | 168 hours<br>500 hours<br>1000 hours | 3 lots x 77 devices |
| High Temperature Gate Bias(HTGB)    | $T_j=150^{\circ}\text{C}$ @ 100% of Max $V_{GSS}$            | 168 hours<br>500 hours<br>1000 hours | 3 lots x 77 devices |

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